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FAIRCHILD

SEMICONDUCTOR TM

74LVQ373 Low Voltage Octal Transparent Latch with 3-STATE Outputs

General Description

The LVQ373 consists of eight latches with 3-STATE outputs for bus organized system applications. The latches appear transparent to the data when Latch Enable (LE) is HIGH. When LE is low, the data satisfying the input timing requirements is latched. Data appears on the bus when the Output Enable (\overline{OE}) is LOW. When \overline{OE} is HIGH, the bus output is in the high impedance state.

Features

- Ideal for low power/low noise 3.3V applications
- Implements patented EMI reduction circuitry
- Available in SOIC JEDEC, SOIC EIAJ and QSOP packages
- Guaranteed simultaneous switching noise level and dynamic threshold performance
- Improved latch-up immunity
- \blacksquare Guaranteed incident wave switching into 75 Ω
- 4 kV minimum ESD immunity

Ordering Code:

Order Number	Package Number	Package Description
74LVQ373SC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide
74LVQ373SJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74LVQ373QSC	MQA20	20-Lead Quarter Size Outline Package (QSOP), JEDEC MO-137, 0.150" Wide

Devices also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering code.



Pin Descriptions

Pin Names	Description			
D ₀ -D ₇	Data Inputs			
LE	Latch Enable Input			
OE	Output Enable Input			
O ₀ -O ₇	3-STATE Latch Outputs			

Connection Diagram



Truth Table

	Outputs		
LE	OE	D _n	O _n
Х	Н	Х	Z
Н	L	L	L
Н	L	Н	Н
L	L	Х	O ₀

 H = HIGH Voltage Level
 L = LOW Voltage Level

 Z = High Impedance
 X = Immaterial

 $O_0 =$ Previous O_0 before HIGH to Low transition of Latch Enable

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Functional Description

The LVQ373 contains eight D-type latches with 3-STATE standard outputs. When the Latch Enable (LE) input is HIGH, data on the D_n inputs enters the latches. In this condition the latches are transparent, i.e., a latch output will change state each time its D-type input changes. When LE is LOW, the latches store the information that was present on the D-type inputs a setup time preceding the

Logic Diagram

HIGH-to-LOW transition of LE. The 3-STATE standard outputs are controlled by the Output Enable (\overline{OE}) input. When \overline{OE} is LOW, the standard outputs are in the 2-state mode. When \overline{OE} is HIGH, the standard outputs are in the high impedance mode but this does not interfere with entering new data into the latches.



Absolute Maximum Ratings(Note 1)

Supply Voltage (V _{CC})	-0.5V to +7.0V
$V_{\rm I} = -0.5V$	–20 mA
$V_I = V_{CC} + 0.5V$	+20 mA
DC Input Voltage (VI)	–0.5V to V _{CC} + 0.5V
DC Output Diode Current (I _{OK})	
$V_{O} = -0.5V$	–20 mA
$V_O = V_{CC} + 0.5V$	+20 mA
DC Output Voltage (V _O)	–0.5V to V_{CC} + 0.5V
DC Output Source	
or Sink Current (I _O)	±50 mA
DC V _{CC} or Ground Current	
(I _{CC} or I _{GND})	±400 mA
Storage Temperature (T _{STG})	-65°C to +150°C
DC Latch-Up Source or	
Sink Current	±300 mA

Recommended Operating Conditions (Note 2)

Supply Voltage (V _{CC})	2.0V to 3.6V
Input Voltage (V _I)	0V to V _{CC}
Output Voltage (V _O)	0V to V _{CC}
Operating Temperature (T _A)	$-40^{\circ}C$ to $+85^{\circ}C$
Minimum Input Edge Rate ($\Delta V/\Delta t$)	
V _{IN} from 0.8V to 2.0V	
V _{CC} @ 3.0V	125 mV/ns

Note 1: The "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. The device should not be operated at these limits. The parametric values defined in the Electrical Characteristics tables are not guaranteed at the absolute maximum ratings. The "Recommended Operating Conditions" table will define the conditions for actual device operation.

Note 2: Unused inputs must be held HIGH or LOW. They may not float.

DC Electrical Characteristics

Symbol	Parameter	V _{cc}	$T_A = +25^{\circ}C$		$T_A = -40^\circ C$ to $+85^\circ C$	Unite	Conditions
Symbol		(V)	Тур	Gua	ranteed Limits	Units	Conditions
V _{IH}	Minimum High Level Input Voltage	3.0	1.5	2.0	2.0	V	$V_{OUT} = 0.1V$ or $V_{CC} - 0.1V$
V _{IL}	Maximum Low Level Input Voltage	3.0	1.5	0.8	0.8	V	$V_{OUT} = 0.1V$ or $V_{CC} - 0.1V$
V _{OH}	Minimum High Level	3.0	2.99	2.9	2.9	V	I _{OUT} = -50 μA
	Output Voltage	3.0		2.58	2.48	V	$V_{IN} = V_{IL} \text{ or } V_{IH} \text{ (Note 3)}$ $I_{OH} = -12 \text{ mA}$
V _{OL}	Maximum Low Level	3.0	0.002	0.1	0.1	V	I _{OUT} = 50 μA
	Output Voltage	3.0		0.36	0.44	V	$V_{IN} = V_{IL} \text{ or } V_{IH} \text{ (Note 3)}$ $I_{OL} = 12 \text{ mA}$
I _{IN}	Maximum Input Leakage Current	3.6		±0.1	±1.0	μA	$V_I = V_{CC},$ GND
I _{OLD}	Minimum Dynamic	3.6			36	mA	V _{OLD} = 0.8V Max (Note 5)
I _{OHD}	Output Current (Note 4)	3.6			-25	mA	V _{OHD} = 2.0V Min (Note 5)
I _{CC}	Maximum Quiescent Supply Current	3.6		4.0	40.0	μΑ	$V_{IN} = V_{CC}$ or GND
I _{OZ}	Maximum 3-STATE Leakage Current	3.6		±0.25	±2.5	μΑ	$V_{I} (OE) = V_{IL}, V_{IH}$ $V_{I} = V_{CC}, GND$ $V_{O} = V_{CC}, GND$
V _{OLP}	Quiet Output Maximum Dynamic V _{OL}	3.3	0.4	0.8		V	(Note 6)(Note 7)
V _{OLV}	Quiet Output Minimum Dynamic V _{OL}	3.3	-0.3	-0.8		V	(Note 6)(Note 7)
V _{IHD}	Maximum High Level Dynamic Input Voltage	3.3	1.7	2.0		V	(Note 6)(Note 8)
V _{ILD}	Maximum Low Level Dynamic Input Voltage	3.3	1.6	0.8		V	(Note 6)(Note 8)

Note 3: All outputs loaded; thresholds on input associated with output under test.

Note 4: Maximum test duration 2.0 ms, one output loaded at a time.

Note 5: Incident wave switching on transmission lines with impedances as low as 75Ω for commercial temperature range is guaranteed.

Note 6: Worst case package.

Note 7: Max number of outputs defined as (n). Data inputs are driven 0V to 3.3V; one output at GND.

Note 8: Max number of Data Inputs (n) switching. (n - 1) inputs switching 0V to 3.3V. Input-under-test switching: 3.3V to threshold (V_{ILD}), 0V to threshold (V_{IHD}), f = 1 MHz.

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AC Electrical Characteristics

		n							
				T _A = +25°C		$T_A = -40^\circ$	C to +85°C		
Symbol	Parameter	V _{cc}	C _L = 50 pF			$C_L = 50 \text{ pF}$		Units	
		(V)	Min	Тур	Max	Min	Max		
t _{PHL}	Propagation Delay	2.7	2.5	9.6	14.8	2.5	16.0	20	
t _{PLH}	D _n to O _n	3.3 ± 0.3	2.5	8.0	10.5	2.5	11.0	ns	
t _{PLH}	Propagation Delay	2.7	2.5	9.6	16.9	2.5	18.0	nc	
t _{PHL}	LE to O _n	$\textbf{3.3}\pm\textbf{0.3}$	2.5	8.0	12.0	2.5	12.5	115	
t _{PZL}	Output Enable Time	2.7	2.5	10.2	18.3	2.5	19.0	20	
t _{PZH}		3.3 ± 0.3	2.5	8.5	13.0	2.5	13.5	115	
t _{PHZ}	Output Disable Time	2.7	1.0	10.8	20.4	1.0	21.0	20	
t _{PLZ}		3.3 ± 0.3	1.0	9.0	14.5	1.0	15.0	ns	
t _{OSHL}	Output to Output Skew	2.7		1.0	1.5		1.5		
t _{OSLH}	(Note 9)	3.3 ± 0.3		1.0	1.5		1.5	115	

Note 9: Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the same direction, either HIGH-to-LOW (t_{OSHL}) or LOW-to-HIGH (t_{OSLH}). Parameter guaranteed by design.

AC Operating Requirements

Symbol	Parameter	V _{cc}	T _A = +25°C C _L = 50 pF		$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$ $C_L = 50 \text{ pF}$	Units	
		(V)	Тур	Guaran	teed Minimum		
t _S	Setup Time,	2.7	0	4.0	4.5	22	
	HIGH or LOW	3.3 ± 0.3	0	3.0	3.0	ns	
t _H	Hold Time,	2.7	0	1.5	1.5		
	HIGH or LOW	3.3 ± 0.3	0	1.5	1.5	ns	
t _W	LE Pulse Width,	2.7	2.4	5.0	6.0	22	
	HIGH	3.3 ± 0.3	2.0	4.0	4.0	115	

Capacitance

Symbol	Parameter	Тур	Units	Conditions			
C _{IN}	Input Capacitance	4.5	pF	V _{CC} = Open			
C _{PD} (Note 10)	Power Dissipation Capacitance	39	pF	$V_{CC} = 3.3V$			

Note 10: C_{PD} is measured at 10 MHz.



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